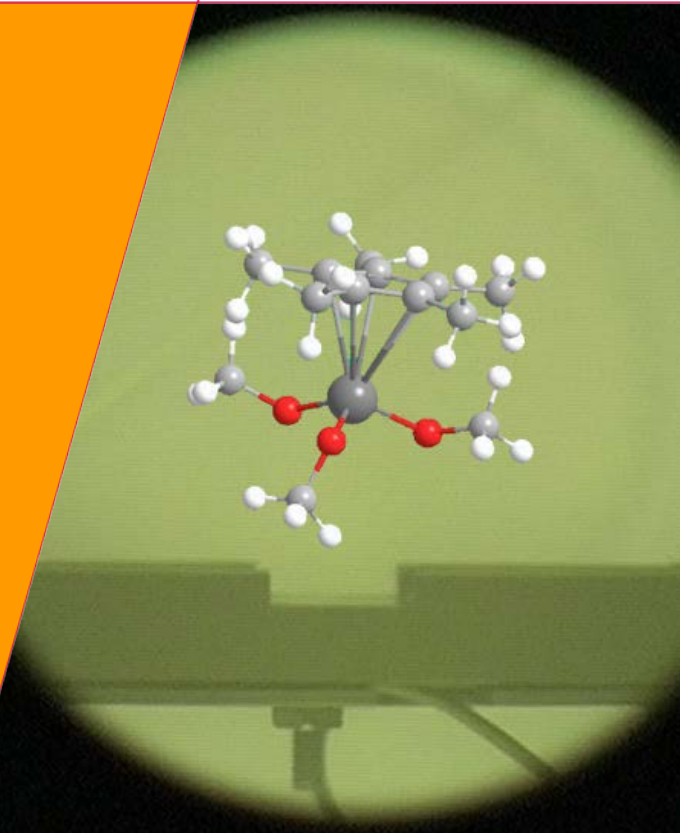


Plasma-Enhanced ALD of TiO_2 : From Ligands to Layers

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Erik Langereis, Anitha Sarkar,
Richard van de Sanden and Erwin Kessels

ALD 2010, Seoul, South Korea
23rd June 2010



TU / **e**

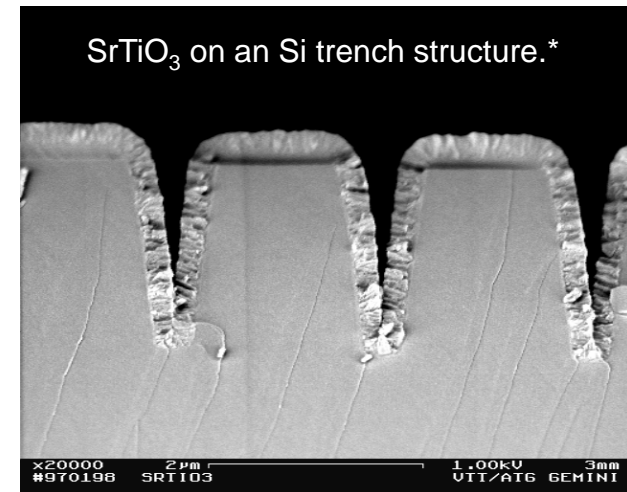
Technische Universiteit
Eindhoven
University of Technology

The research leading to these results has received
funding from the MaxCaps Research Project (Medea+).

Where innovation starts

- **Motivation**
- **Experimental**
 - ALD reactors & diagnostics (spectroscopic ellipsometry, RBS)
 - Available precursors for TiO₂
- **Results**
 - Growth per cycle as a function of substrate temperature
 1. [Ti(OⁱPr)₄]
 2. [Ti(Cp^{Me})(OⁱPr)₃]
 3. [Ti(Cp^{*})(OMe)₃]
 4. [Ti(Cp^{Me})(NMe₂)₃]
 - Film composition and overview
 - Reactivity of ligands and possible reaction mechanism
- **Conclusions**

- Many applications require TiO_2
- **Mixed Oxides**
 - SrTiO_3 (STO) and BaSrTiO_3 (BST)
 - **Ultra-high- k dielectric** for DRAM trench capacitors
- **Requirements**
 - Ultra-thin films
 - Good conformality
 - Wide range of deposition temperatures
 - Control of stoichiometry/atomic composition

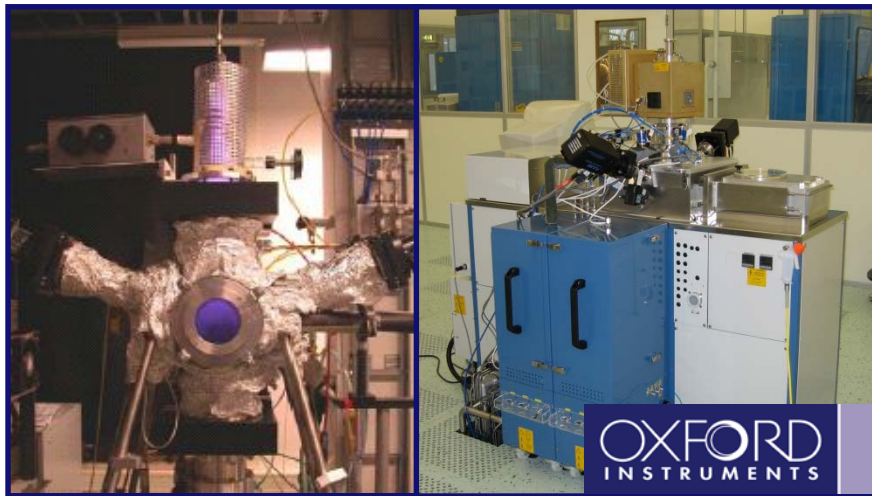


*From: M. Vehkamäki *et al.*, *Electrochem. Solid-State Lett.*, **2**, 504 (1999).

Why use a plasma?

- **Increased reactivity** (radicals, electrons, ions)
- **Allows for depositions at low temperatures**
- **A wider range of precursors can be used**, e.g. $[\text{Ti}(\text{Cp}^x)\text{L}_3]$

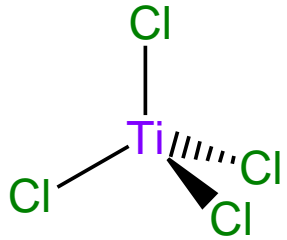
Remote Plasma ALD Reactors



ALD-I (home-built)

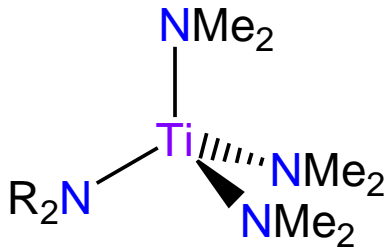
FlexAL™

- 100 mm n-type Si{100} substrates
- *In situ* spectroscopic ellipsometry (SE)
 - Film thickness & growth per cycle (GPC)
- RBS and ERD (H)
 - Absolute areal density (atoms cm^{-2})



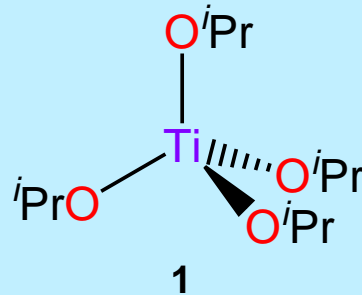
Halides

- Film contamination
- Corrosive by-products (HX)

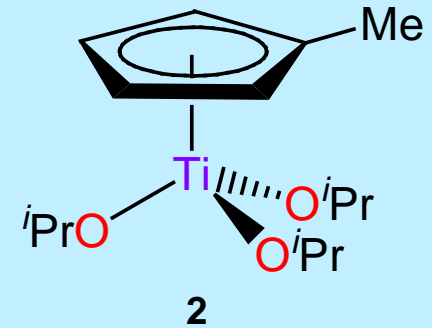
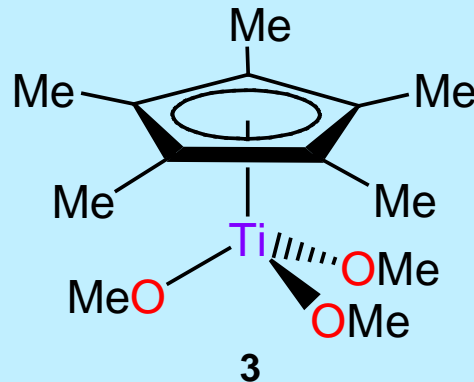


Homoleptic Amides

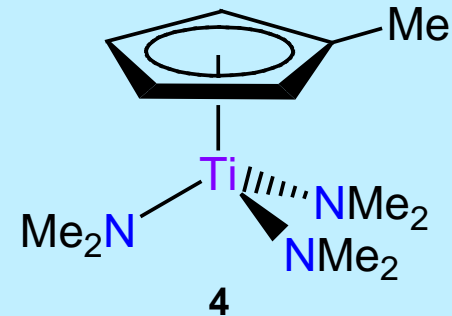
- Low stability



Homoleptic Alkoxides

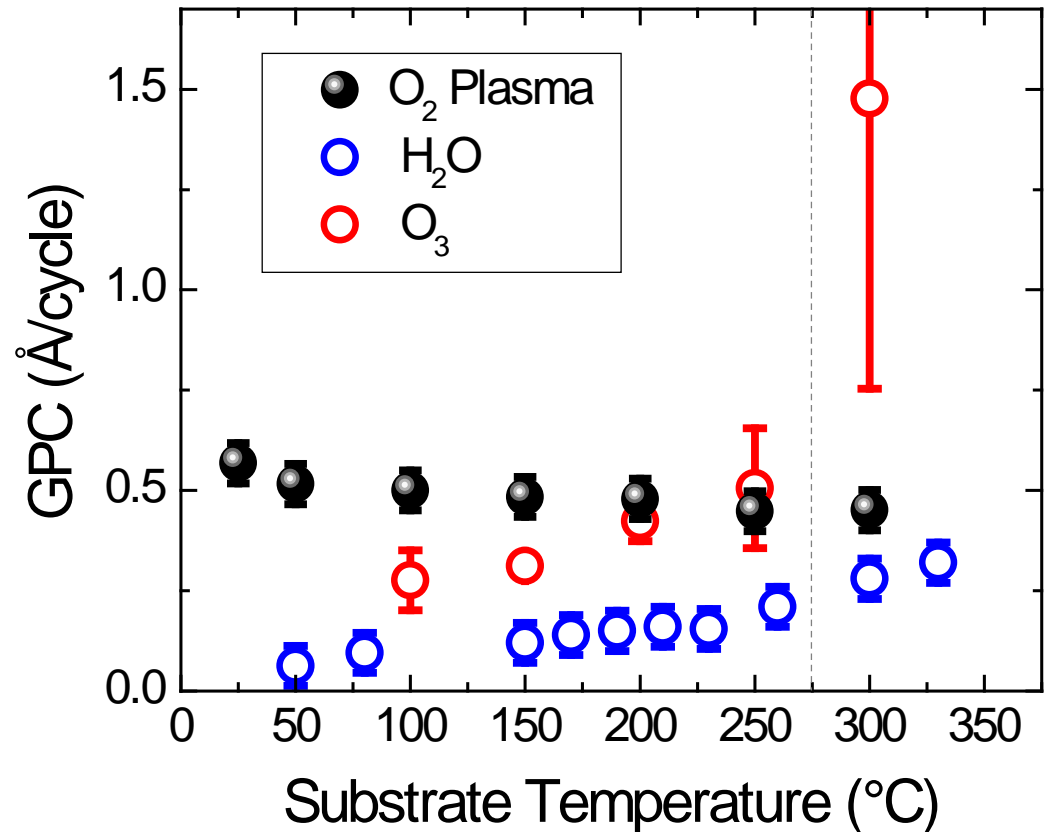


Heteroleptic Cp-Compounds (2-4)

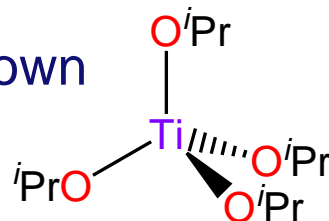


For more on ligand possibilities, see: N. Blasco *et al.*, *Sr and Ti Precursors Development for Next Generation Thin Film Application*, 216th ECS Meeting, Vienna (2009).

- **[Ti(O*i*Pr)₄]**
 - “TTIP”
 - A **standard** TiO₂ precursor
 - Homoleptic alkoxide
 - Tendency to dimerise
 - Decomposition at 300 °C
- **ALD with water and ozone**
 - Increase in GPC with increasing substrate temperature:
 - **Thermally-driven** process.
- **Plasma ALD**
 - **Consistently high GPC** down to room temperature.



Precursor decomposition at $T_s >$ dashed line.



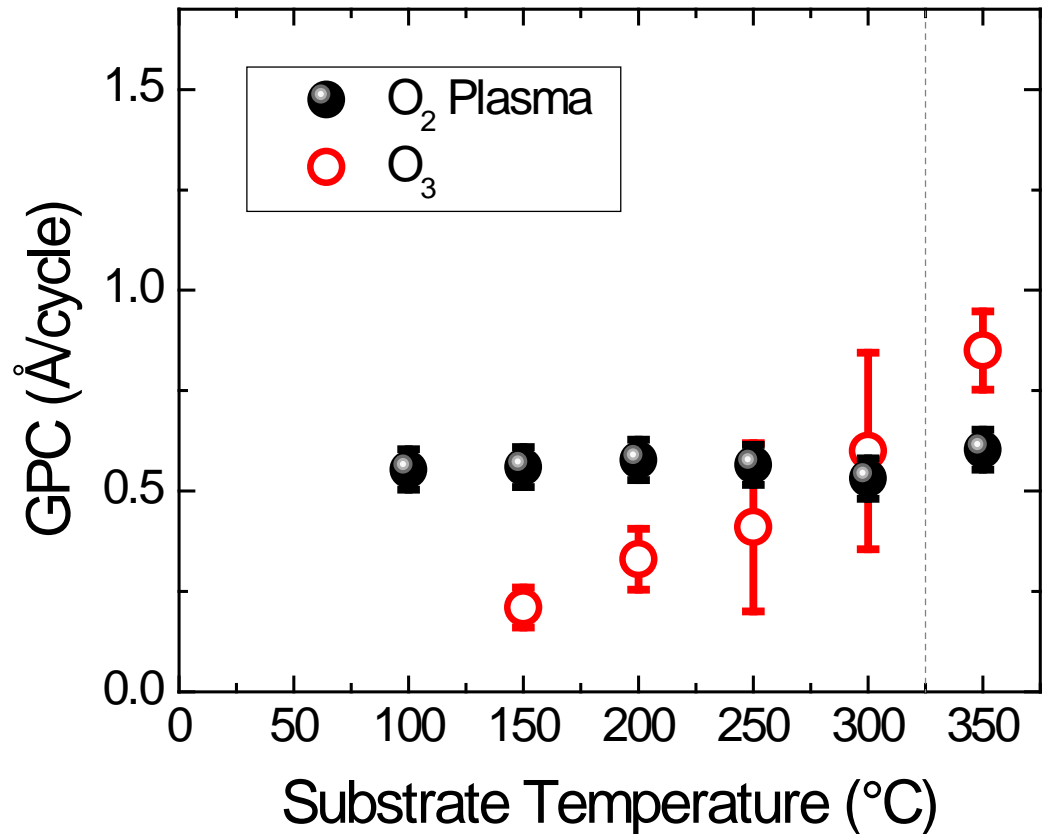
H₂O process: Q. Xie *et al.*, *J. Appl. Phys.*, **102**, 083521 (2007).

O₃ process: P. Williams at ALD 2008, Bruges, Belgium.

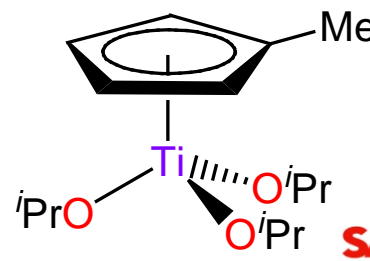
Growth per Cycle (GPC) • Precursor #2

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- **[Ti(Cp^{Me})(OⁱPr)₃]**
 - Cp^{Me} for **increased stability and volatility**
 - No oligomerisation
 - Decomposition above 300 °C (β-H on ⁱPr groups)
- **Not reactive with water in ALD process.**
- **Thermally-driven mechanism for ozone.**
- **Flat GPC profile for plasma process.**
- **Comparable GPC to #1.**

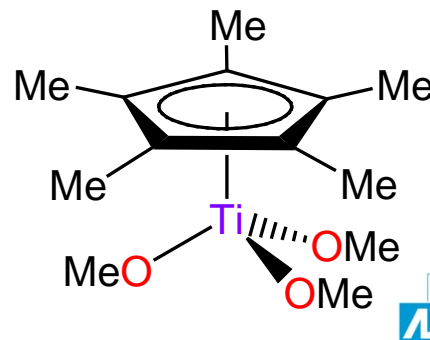
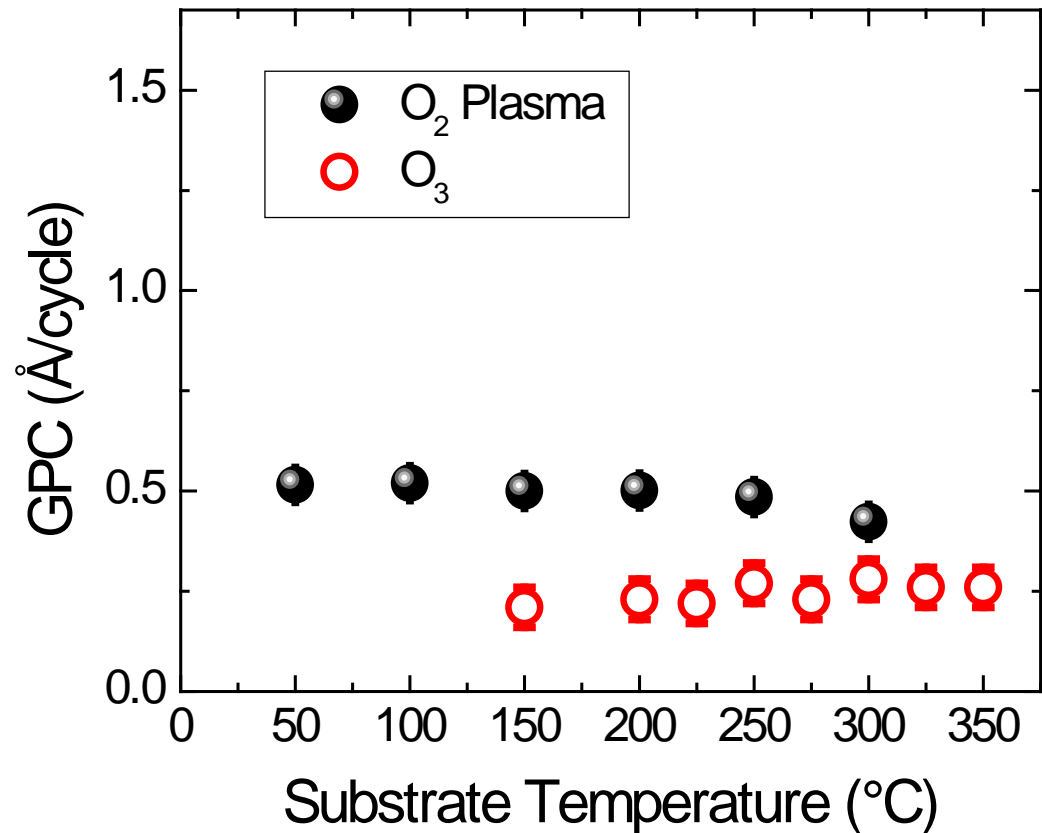


Precursor decomposition at $T_s >$ dashed line.



O₃ process: P. Williams at ALD 2008, Bruges, Belgium.

- **[Ti(Cp*)(OMe)₃]**
 - “Ti-Star” or “StarTi”
 - No obvious decomposition
 - OMe groups have no β-H
- **Similar GPC to #1 and #2.**
- **Increase in GPC with temperature for ozone less prominent.**
- **Preliminary DFT calculations**
 - Full chemical bonding does not take place with OH surface groups.*
 - H-bonding *via* OMe groups.
 - Cp^x left on surface.



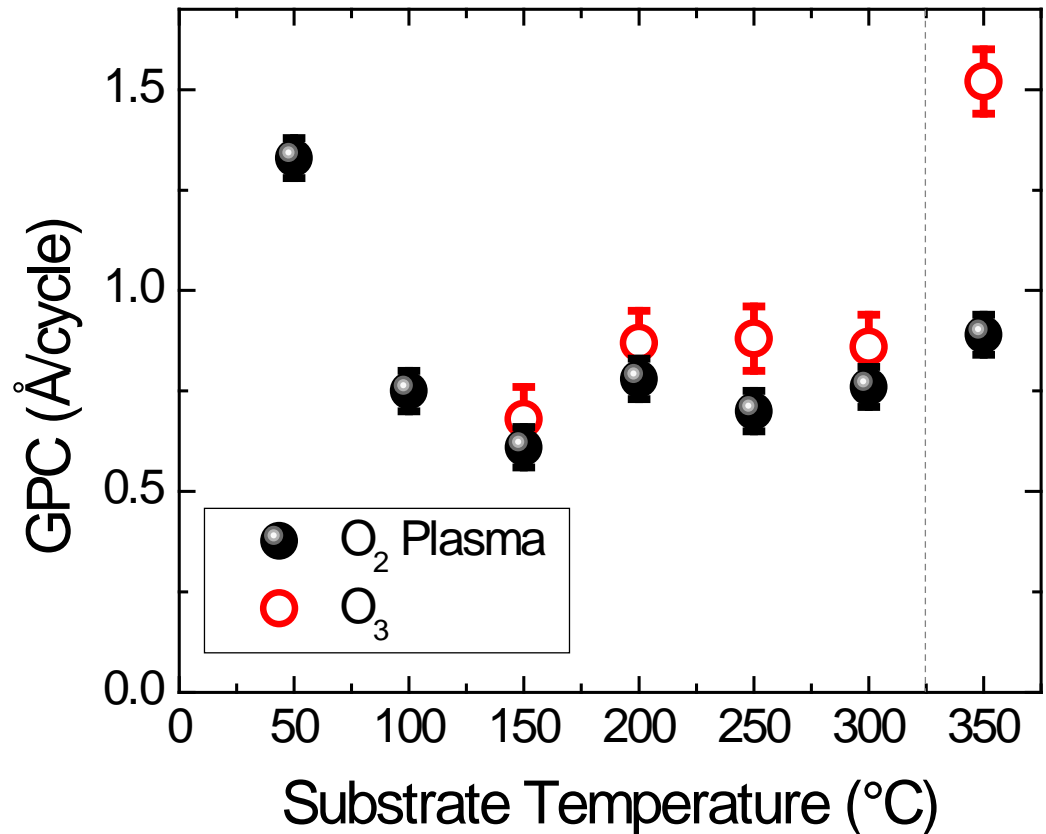
O₃ process: R. Katamreddy *et al.*, *ECS Trans.*, **25**, 217 (2009).

*S. D. Elliott *et al.* at ALD 2010, 22nd June.

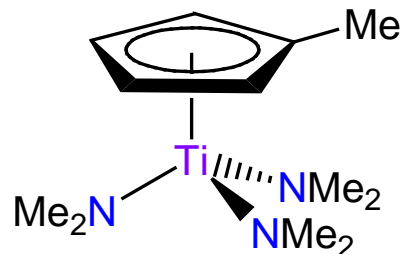
Growth per Cycle (GPC) • Precursor #4

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- **[Ti(Cp^{Me})(NMe₂)₃]**
 - Possibility of oxides and nitrides.
 - NMe₂ more reactive towards oxidants.
- **GPC of plasma and ozone processes follow similar trend.**
- **Higher GPC than #1-3.**
- **Reactivity of NMe₂ ligands higher than OR.**
- **This reactivity reduces at $T_s < 200$ °C.**



Precursor decomposition at $T_s >$ dashed line.

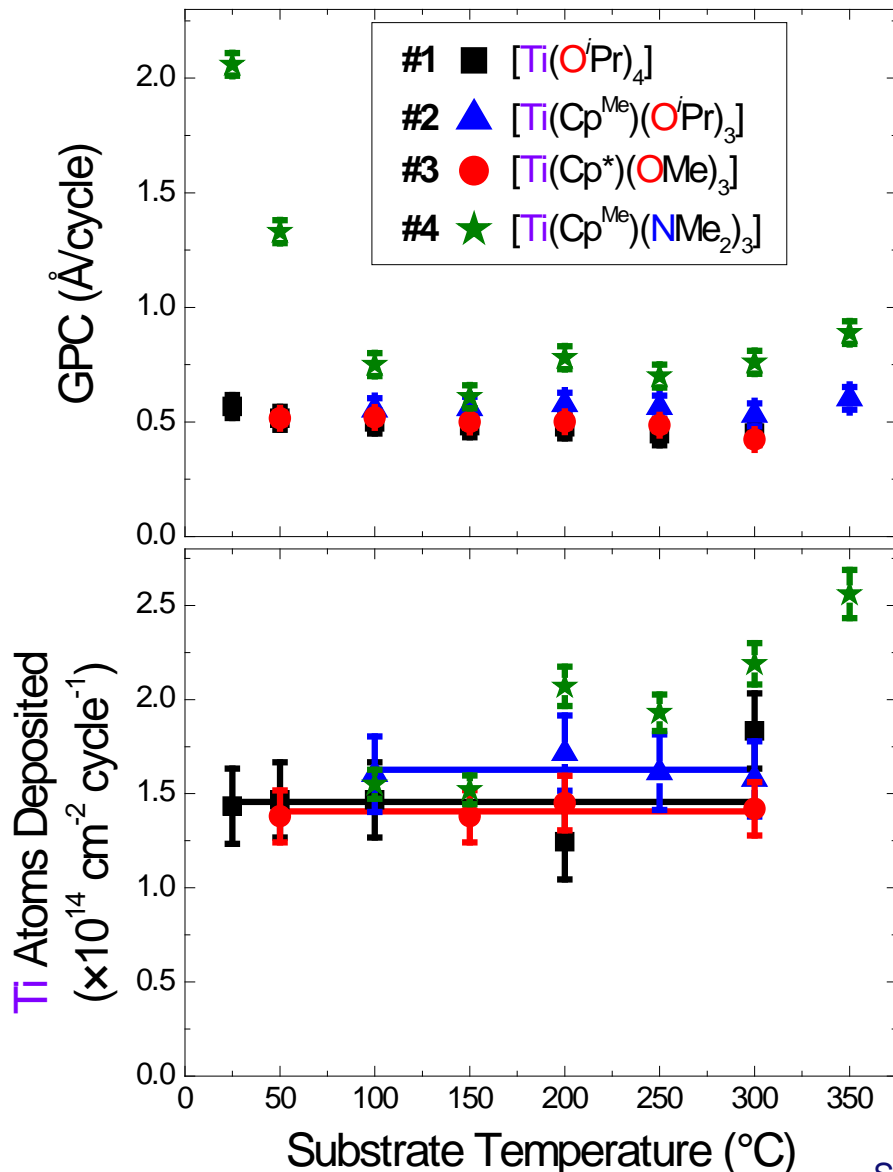


O₃ process: P. Williams at ALD 2008, Bruges, Belgium.

See also: A. Sarkar at the 218th ECS meeting, Las Vegas, Oct. 2010.

Overview & Ti Atoms Deposited per Cycle

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- **O/Ti ratio = 2.0 ± 0.1**
- **H present**
 - Generally <4 at.%.
 - #4 at 100 °C, ~7 at.%
- **Ti/cycle**
 - Not affected by film density
 - #2 and #3 (Cp/OR) – consistent
 - #4 – increases with temperature
- **OR + Cp^{Me}**
 - most consistent GPCs and Ti/cycles
- **NR₂ (+ Cp^{Me})**
 - higher reactivity, increasing with temperature.

- **Ti-OR**
 - GPCs of $\sim 0.5 \text{ \AA/cycle}$ typically
 - OMe ligand undergoes **H-bonding**
- **Ti-NR₂**
 - **More reactive** than alkoxide ligands
 - Full thermal **reaction** with surface groups at $T_s \geq 200 \text{ }^\circ\text{C}$
- **Ti-Cp^x**
 - No reactivity towards water
 - Low reactivity towards ozone
 - Plasma best option at lower temperatures
 - **Cannot H-bond**
- **The Ti precursor should have some ligands which are, at least, able to H-bond with the surface.**

- H_2O , O_3 and an O_2 plasma give very different results for the same ligands.
- **Two oxide-ALD factors:**
 1. Reactivity of the **precursor** with the surface groups
 2. Reactivity of the **oxidant** with the surface groups
- For **plasma ALD**, the precursor reactivity with the substrate surface (1) is, in practice, **the only limiting step**.
- More reactive ligands can give a higher growth per cycle.
- Reactivity of ligands in **Ti** compounds towards surface groups at low temperature:
$$\text{Cp}^x < \text{OR} < \text{NR}_2$$
- **Ability to H-bond with surface groups is key to the reaction mechanism.**
- **Cp-based precursors for microelectronics applications:**
 - Give good ALD behaviour
 - Cp^x ligands provide stability to the precursors